

Form PTO-1449
(Rev. 2-32)U.S. Department of Commerce
Patent & Trademark OfficeAtty. Docket No.
005329 ALRT/MASK/RTSerial No.
UNKNOWNINFORMATION DISCLOSURE STATEMENT
(Use several sheets if necessary)Applicant:
Shirley HEMAR et al.Filing Date:
Concurrently herewith

Group

J1017 U.S. PTO
09/07/95
06/07/01

U.S. PATENT DOCUMENTS

Examiner Initial	Document Number	Date	Name	Class	Sub-Class	Filing Date (if appropriate)
JS	6,016,357	1/18/00	Neary et al.	382	144	1/16/97
JS	5,795,688	8/18/98	Burdorf et al.	430	30	8/14/96
JS	6,072,898	6/6/00	Beaty et al.	382	146	6/16/98
JS	6,148,097	11/14/00	Nakayama et al.	382	141	6/5/96
JS	6,075,883	6/13/00	Stern et al.	382	144	11/12/96
JS	6,025,905	2/15/00	Sussman	356	3.01	12/31/96
JS	6,052,478	4/18/00	Wihl et al.	382	144	10/9/96
JS	6,018,392	1/25/00	Tzu et al.	356	351	10/23/98
JS	6,081,659	6/27/00	Garza et al.	395	500.22	4/26/99
JS	6,078,738	6/20/00	Garza et al.	395	500.22	5/8/97

FOREIGN PATENT DOCUMENTS

Document	Date	Country	Class	Sub-class	Translation Yes/No
JS 0 628 806 A2	12/14/94	Europe	—	—	

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

JS	Budd, Russell A., et al., "A New Tool for Phase Shift Mask Evaluation, the Stepper Equivalent Aerial Image Measurement System - AIMS™," SPIE Vol. 2087 Photomask Technology and Management (1993).
JS	Schenker, Richard, "Comparison of Single and Dual Exposure Phase Shift Mask Approaches for Poly Gate Patterning," SPIE, Vol. 3546, September 1998.

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John Strege

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6/3/04

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JS	5,745,168	4/28/98	Ninomiya	348	191	
JS	5,744,381	4/28/98	Tabata et al.	438	16	
JS	5,481,624	1/2/96	Kamon	382	144	
JS	5,441,834	8/15/95	Takekuma et al.	430	5	
JS	5,272,116	12/21/93	Hosono	437	228	
JS	4,922,308	5/1/90	Noguchi et al.	356	237	
JS	4,148,065	4/3/79	Nakagawa et al.	358	101	
JS	5,572,598	11/5/96	Wihl et al.	382	144	
JS	6,091,845	7/18/00	Pierrat et al.	382	144	2/24/98

FOREIGN PATENT DOCUMENTS

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OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

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